

Product Summary

Device	V _{(BR)DSS}	R _{DS(ON)} max	I _D max T _A = 25°C
01	201/	$0.5\Omega @ V_{GS} = 4.5V$	1030mA
Q1	20V	0.9Ω @ V _{GS} = 1.8V	740mA
00	00) (1.0Ω @ V _{GS} = -4.5V	-700mA
Q2	-20V	2.0Ω @ V _{GS} = -1.8V	-460mA

Description and Applications

This new generation MOSFET has been designed to minimize the on-state resistance ($R_{DS(on)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Power management functions
- Battery Operated Systems and Solid-State Relays
- Load switch

Features and Benefits

- Low On-Resistance
- Low Gate Threshold Voltage V_{GS(th)} <1V
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Complementary Pair MOSFET
- Ultra-Small Surface Mount Package
- ESD Protected Gate to 2kV HBM
- Lead Free/RoHS Compliant (Note 1)
- "Green" Device, Halogan and Antimony Free (Note 2)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

- Case: SOT563
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.003 grams (approximate)

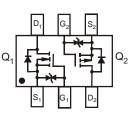


Top View

SOT563



Bottom View



Equivalent Circuit

Ordering Information (Note 3)

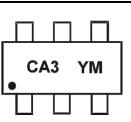
Part Number	Case	Packaging
DMC2400UV-7	SOT563	3000/Tape & Reel
DMC2400UV-13	SOT563	10000/Tape & Reel

Notes: 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. No purposely added lead. Halogen and Antimony free

2. Diodes Inc.'s "Green" policy can be found on our website at http://www.diodes.com.

3. For packaging details, go to our website at http://www.diodes.com.

Marking Information



CA3 = Product Type Marking Code YM = Date Code Marking Y = Year (ex: Y = 2011) M = Month (ex: 9 = September)

Date Code Key

Bate Code Hoy												
Year	201	1	2012		2013	20	14	2015		2016	2	2017
Code	Y		Z		А	I	3	С		D		E
Month	Jan	Feb	Mar	Apr	Мау	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	Ν	D



Maximum Ratings - Q1 N-CHANNEL @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Value	Units		
Drain-Source Voltage			V _{DSS}	20	V
Gate-Source Voltage			V _{GSS}	±12	V
	Steady State	T _A = 25°C T _A = 70°C	ID	1030 800	mA
Continuous Drain Current (Note 5) V_{GS} = 4.5V	t<10s	T _A = 25°C T _A = 70°C	ID	1150 900	mA
	Steady State	T _A = 25°C T _A = 70°C	ID	740 570	mA
Continuous Drain Current (Note 5) V_{GS} = 1.8V	t<10s	T _A = 25°C T _A = 70°C	ID	870 700	mA
Pulsed Drain Current (10µs pulse, duty cycle = 1%)	I _{DM}	3	А		
Maximum Body Diode continuous Current	ls	800	mA		

Maximum Ratings - Q2 P-CHANNEL @T_A = 25°C unless otherwise specified

Characteristic		Symbol	Value	Units	
Drain-Source Voltage		V _{DSS}	-20	V	
Gate-Source Voltage			V _{GSS}	±8	V
	Steady State	T _A = 25°C T _A = 70°C	ID	-700 -550	mA
Continuous Drain Current (Note 5) $V_{GS} = -4.5V$	t<10s	T _A = 25°C T _A = 70°C	I _D	-820 -640	mA
	Steady State	T _A = 25°C T _A = 70°C	ID	-460 -350	mA
Continuous Drain Current (Note 5) V_{GS} = -1.8V	t<10s	T _A = 25°C T _A = 70°C	ID	-550 -420	mA
Pulsed Drain Current (10µs pulse, duty cycle = 1%)	I _{DM}	-2	А		
Maximum Body Diode continuous Current			ls	-800	mA

Thermal Characteristics @T_A = 25°C unless otherwise specified

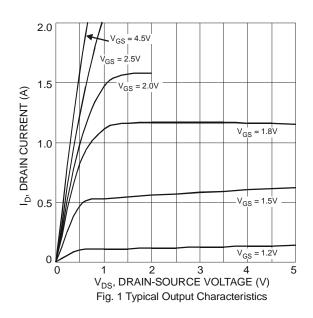
Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 4)	_	PD	0.45	W
Thermal Resistance, Junction to Ambient (Note 4)	Steady state	D	281	°C/W
Thermal Resistance, Junction to Ambient (Note 4)	t<10s	$R_{ extsf{ heta}JA}$	210	°C/W
Total Power Dissipation (Note 5)		PD	1	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	Р	129	°C/W
memai Resistance, sunction to Ambient (Note 5)	t<10s	$R_{ extsf{ heta}JA}$	97	°C/W
Operating and Storage Temperature Range		T _{J,} T _{STG}	-55 to +150	°C

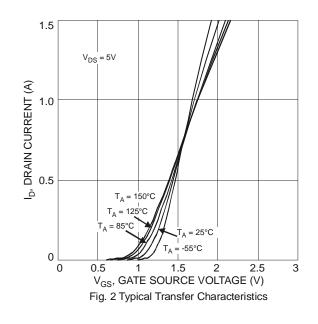


Electrical Characteristics - Q1 N-CHANNEL @T_A = 25°C unless otherwise specified

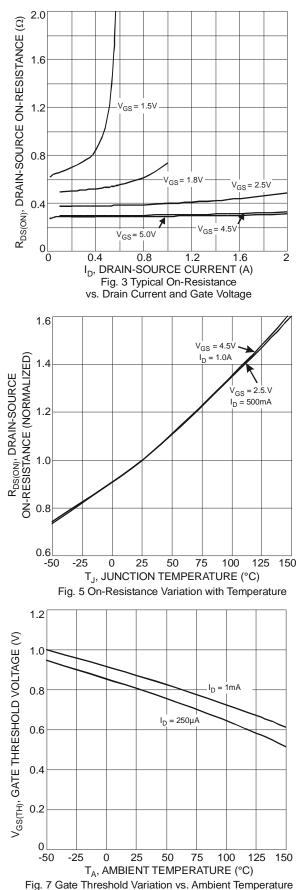
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)						
Drain-Source Breakdown Voltage	BV _{DSS}	20	-	-	V	$V_{GS} = 0V, I_D = 1mA$
Zero Gate Voltage Drain Current T _J = 25°C	IDSS	-	-	100	nA	$V_{DS} = 20V, V_{GS} = 0V$
Gate-Source Leakage	1	-	-	±1	μA	$V_{GS} = \pm 5V, V_{DS} = 0V$
Gale-Source Leakage	I _{GSS}	-	-	±4.0	μΑ	$V_{GS} = \pm 8V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 6)						
Gate Threshold Voltage	V _{GS(th)}	0.5	-	0.9	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
		-	0.3	0.48		$V_{GS} = 5.0V, I_D = 200mA$
		-	0.35	0.5	Ω	$V_{GS} = 4.5V, I_D = 200mA$
Static Drain-Source On-Resistance	R _{DS (ON)}	-	0.45	0.7		$V_{GS} = 2.5V, I_D = 200mA$
		-	0.55	0.9		$V_{GS} = 1.8V, I_D = 100mA$
		-	0.65	1.5		$V_{GS} = 1.5V, I_D = 50mA$
		-	2	-		$V_{GS} = 1.2V, I_D = 1mA$
Forward Transfer Admittance	Y _{fs}	-	1.4	-	S	$V_{DS} = 3V, I_D = 200mA$
Diode Forward Voltage	V _{SD}	-	0.7	1.2	V	$V_{GS} = 0V, I_{S} = 500mA,$
DYNAMIC CHARACTERISTICS (Note 7)				•	•	
Input Capacitance	Ciss	-	37.1	-		$V_{DS} = 10V, V_{GS} = 0V,$
Output Capacitance	Coss	-	6.5	-	pF	$v_{DS} = 10V, v_{GS} = 0V,$ f = 1.0MHz
Reverse Transfer Capacitance	C _{rss}	-	4.8	-		
Gate Resistance	Rg	-	68	-	Ω	$V_{DS} = 0V, V_{GS} = 0V,$
Total Gate Charge	Qg	-	0.5	-		$1/2 = -4 = 1/2 = -10^{1/2}$
Gate-Source Charge	Q _{gs}	-	0.07	-	nC	$V_{GS} = 4.5V, V_{DS} = 10V,$ In = 250mA
Gate-Drain Charge	Q _{gd}	-	0.1	-		ID = 230IIIA
Turn-On Delay Time	t _{D(on)}	-	4.06	-		
Turn-On Rise Time	tr	-	7.28	-		$V_{DD} = 10V, V_{GS} = 4.5V,$
Turn-Off Delay Time	t _{D(off)}	-	13.74	-	ns	$R_L = 47\Omega, R_G = 10\Omega,$ $I_D = 200mA$
Turn-Off Fall Time	t _f	-	10.54	-]	ID = 20011A

 Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
Short duration pulse test used to minimize self-heating effect.
Guaranteed by design. Not subject to product testing. Notes:









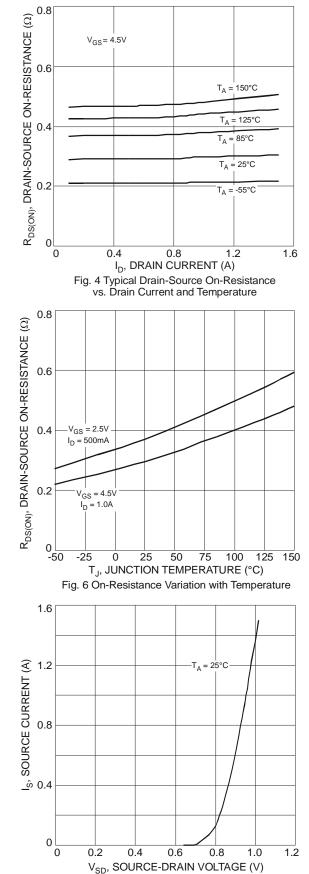


Fig. 8 Diode Forward Voltage vs. Current

 $T_A = -55^{\circ}C$

18 20

P_W = 10µs

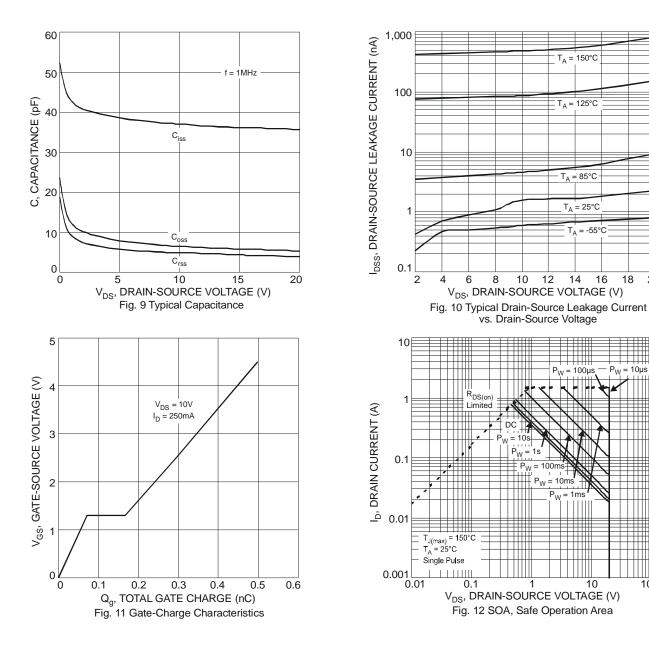
14 16

= 1ms

10

100



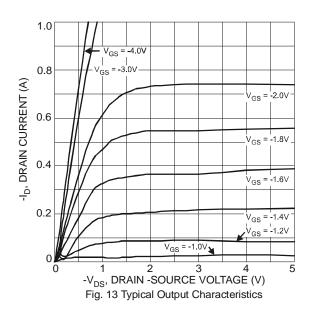


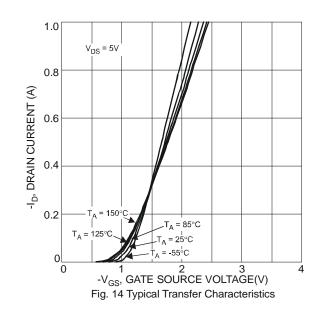


Electrical Characteristics - Q2 P-CHANNEL @T_A = 25°C unless otherwise specified

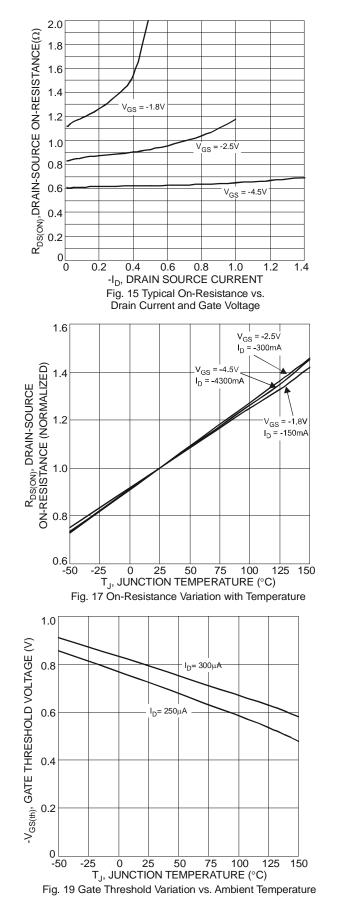
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)	Symbol		iyp	IVIAN	Unit	Test condition
Drain-Source Breakdown Voltage	BV _{DSS}	-20	-	-	V	$V_{GS} = 0V, I_{D} = -1mA$
Zero Gate Voltage Drain Current $T_J = 25^{\circ}C$	I _{DSS}	-	-	-100	nA	$V_{DS} = -20V, V_{GS} = 0V$
		-	-	±1.0		$V_{GS} = \pm 5V, V_{DS} = 0V$
Gate-Source Leakage	I _{GSS}	-	-	±5.0	μA	$V_{GS} = \pm 8V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 6)						÷
Gate Threshold Voltage	V _{GS(th)}	-0.5	-	-1.0	V	$V_{DS} = V_{GS}, I_D = -250 \mu A$
		-	0.67	0.97		$V_{GS} = -5V, I_D = -100mA$
			0.7	1.0		$V_{GS} = -4.5V, I_D = -100mA$
Static Drain-Source On-Resistance	Р	-	0.9	1.5	Ω	$V_{GS} = -2.5V, I_D = -80mA$
Static Drain-Source On-Resistance	R _{DS (ON)}	-	1.2	2.0	52	$V_{GS} = -1.8V, I_D = -40mA$
		-	1.5	3.0	-	$V_{GS} = -1.5V, I_D = -30mA$
		-	5	-		$V_{GS} = -1.2V, I_D = -1mA$
Forward Transfer Admittance	Y _{fs}	-	0.7	-	S	$V_{DS} = -3V, I_{D} = -100mA$
Diode Forward Voltage	V _{SD}	-	-0.75	-1.2	V	$V_{GS} = 0V, I_{S} = -330mA,$
DYNAMIC CHARACTERISTICS (Note 7)						
Input Capacitance	C _{iss}	-	46.1	-		
Output Capacitance	Coss	-	7.2	-	pF	$V_{DS} = 10V, V_{GS} = 0V,$ f = 1.0MHz
Reverse Transfer Capacitance	C _{rss}	-	4.9	-		1 - 1.00012
Gate Resistance	Rg	-	14.3	-	Ω	$V_{DS} = 0V, V_{GS} = 0V,$
Total Gate Charge V _{GS} = -4.5V	Qq	-	0.5	-		
Total Gate Charge V _{GS} = -10V	Qg	-	0.85	-		V _{DS} = -10V, I _D = -250mA
Gate-Source Charge	Q _{gs}	-	0.09	-	nC	
Gate-Drain Charge	Q _{gd}	-	0.09	-		
Turn-On Delay Time	t _{D(on)}	-	8.5	-		
Turn-On Rise Time	tr	-	4.3	-		$V_{DD} = -3V, V_{GS} = -2.5V,$
Turn-Off Delay Time	t _{D(off)}	-	20.2	-	ns	$R_{L} = 300\Omega, R_{G} = 25\Omega,$
Turn-Off Fall Time	t _f	-	19.2	-	1	I _D = -100mA

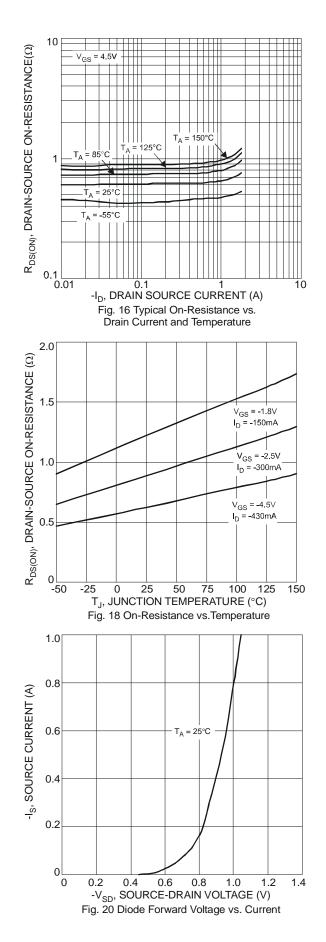
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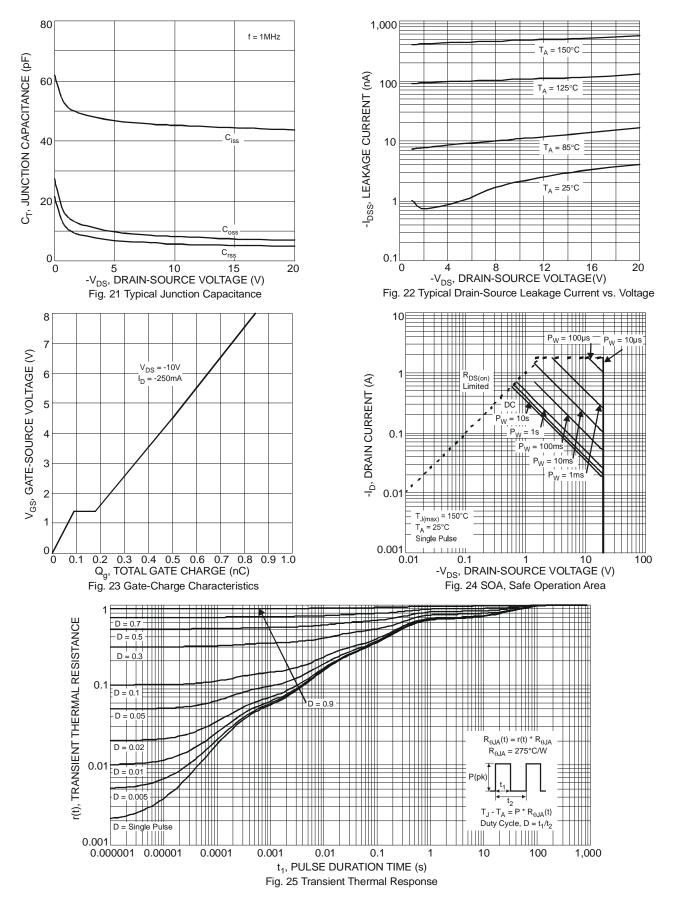






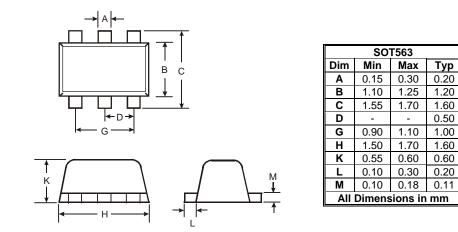




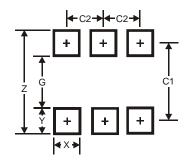




Package Outline Dimensions



Suggested Pad Layout



Dimensions	Value (in mm)
Z	2.2
G	1.2
Х	0.375
Y	0.5
C1	1.7
C2	0.5



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